

**Search Notes**

Application/Control No.

10/052,870

Examiner

Jason M. Perilla

Applicant(s)/Patent under  
Reexamination

SHI ET AL.

Art Unit

26346

**SEARCHED**

| Class | Subclass | Date      | Examiner |
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| 375   | 219      | 6/15/2005 | JP       |
|       | 316      | 6/15/2005 | JP       |
|       | 324      | 6/15/2005 | JP       |
|       | 344      | 6/15/2005 | JP       |
|       | 345      | 6/15/2005 | JP       |
|       | 346      | 6/15/2005 | JP       |
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| 455   | 130      | 6/15/2005 | JP       |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|                                   | DATE      | EXMR |
|-----------------------------------|-----------|------|
| East<br>USPAT USPGPUB<br>EPO JPO  | 6/15/2005 | JP   |
| Inventor Name Search<br>EAST/EDAN | 6/15/2005 | JP   |
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